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<i>Title:</i>	Role of Interfaces in the Design of Ultra-high Strength, Radiation Damage Tolerant Nanocomposites
<i>Author(s):</i>	Amit Misra, Yong Wang, Mike Nastasi, Kevin Baldwin, Dhriti Bhattacharyya, Qiangmin Wei, Nan Li, Nathan Mara, Xinghang Zhang, Engang Fu, Osman Anderoglu, and Hongqi Li
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## **Role of Interfaces in the design of ultra-high strength, radiation damage tolerant nanocomposites**

Presenting author: Amit Misra

Los Alamos National Laboratory,  
Los Alamos, NM 87545.  
E-mail: amisra@lanl.gov

The combination of high strength and high radiation damage tolerance in nanolaminate composites can be achieved when the individual layers in these composites are only a few nanometers thick and contain special interfaces that act both as obstacles to slip, as well as sinks for radiation-induced defects. The morphological and phase stabilities and strength and ductility of these nano-composites under ion irradiation are explored as a function of layer thickness, temperature and interface structure. Magnetron sputtered metallic multilayers such as Cu-Nb and V-Ag with a range of individual layer thickness from approximately 2 nm to 50 nm and the corresponding 1000 nm thick single layer films were implanted with helium ions at room temperature. Cross-sectional Transmission Electron Microscopy (TEM) was used to measure the distribution of helium bubbles and correlated with the helium concentration profile measured via ion beam analysis techniques to obtain the helium concentration at which bubbles are detected in TEM. It was found that in multilayers the minimum helium concentration to form bubbles (approximately 1 nm in size) that are easily resolved in through-focus TEM imaging was several atomic %, orders of magnitude higher than that in single layer metal films. This observation is consistent with an increased solubility of helium at interfaces that is predicted by atomistic modeling of the atomic structures of fcc-bcc interfaces. At helium concentrations as high as 7 at.%, a uniform distribution of 1 nm diameter bubbles results in negligible irradiation hardening and loss of deformability in multilayers with layer thicknesses of a few nanometers. The control of atomic structures of interfaces to produce high helium solubility at interfaces is crucial in the design of nano-composite materials that are radiation damage tolerant. Reduced radiation damage also leads to a reduction in the irradiation hardening, particularly at layer thickness of approximately 5 nm and below. The strategies for design of radiation-tolerant structural materials based on the knowledge gained from this work will be discussed.

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# Role of Interfaces in the design of ultra-high strength, radiation damage tolerant nanocomposites

**Presented by:** Amit Misra,

**Collaborators:** Yong Wang, Mike Nastasi

J. Kevin Baldwin

Dhriti Bhattacharyya

Qiangmin Wei

Nan Li

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Xinghang Zhang (Texas A&M), Engang Fu, Osman Anderoglu, Hongqi Li

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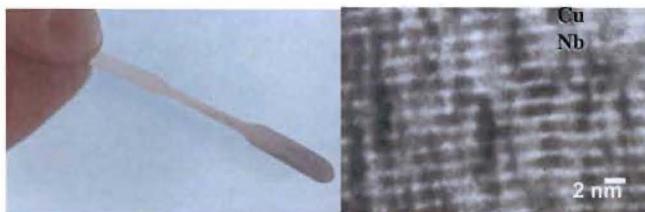
# Objectives

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- Determine the critical concentration of implanted helium at which bubbles nucleate at different interfaces.
- Explore the effect of ion implantation induced defects (particularly He bubbles) on irradiation hardening.

# Approach

## *Synthesis of nanostructured materials (CINT)*

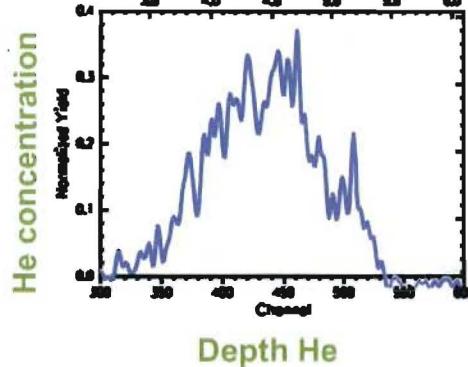


## *Ion irradiation (IBML)*

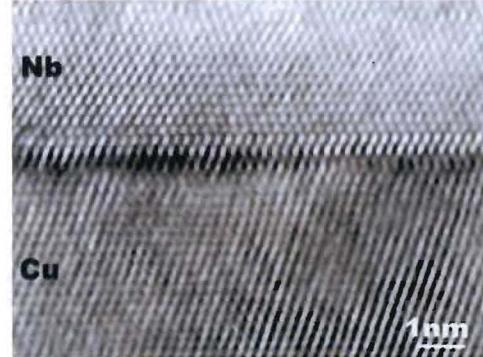


## *Characterization*

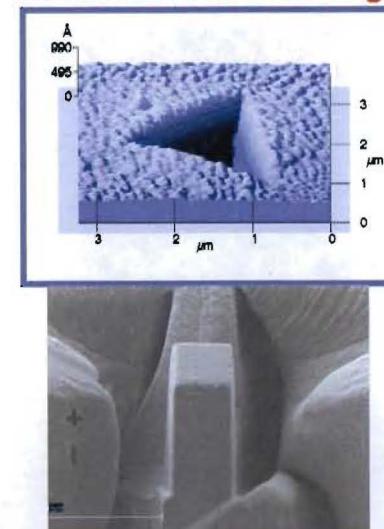
### *Ion-beam analysis*



### *HRTEM (EML)*

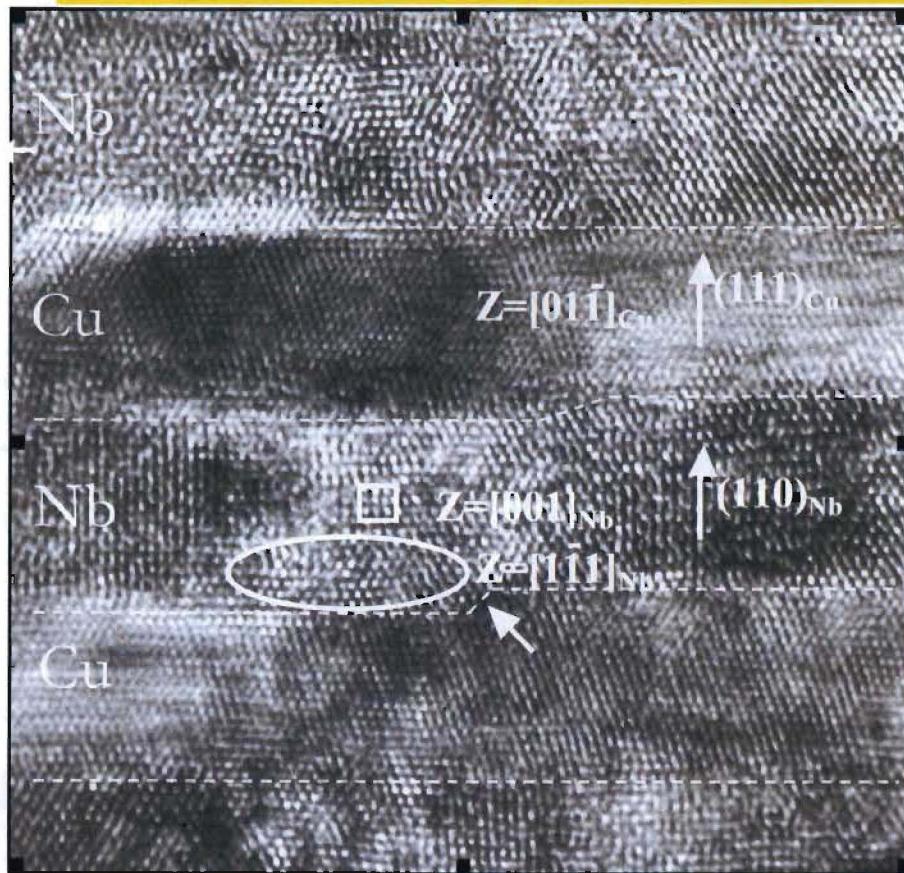


### *Nanomechanical testing (CINT)*

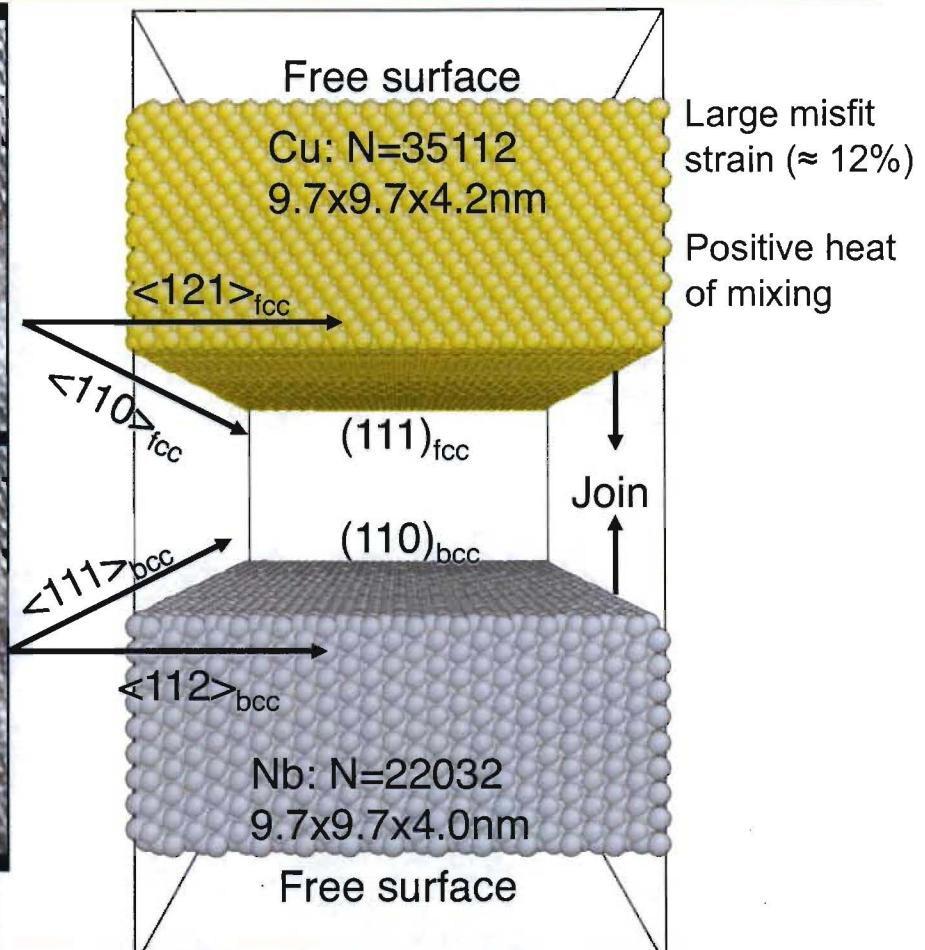


# FCC-BCC Model System:

## *integrate experiments with atomistic modeling*



At 300K, ion beam mixing is not expected in immiscible Cu-Nb system. [Ref: Averback, et al., Appl. Phys. A (1986)].



Atomistic models created by joining fcc-Cu and bcc-Nb in the experimentally observed Kurdjumov-Sachs (KS) orientation relation (OR)

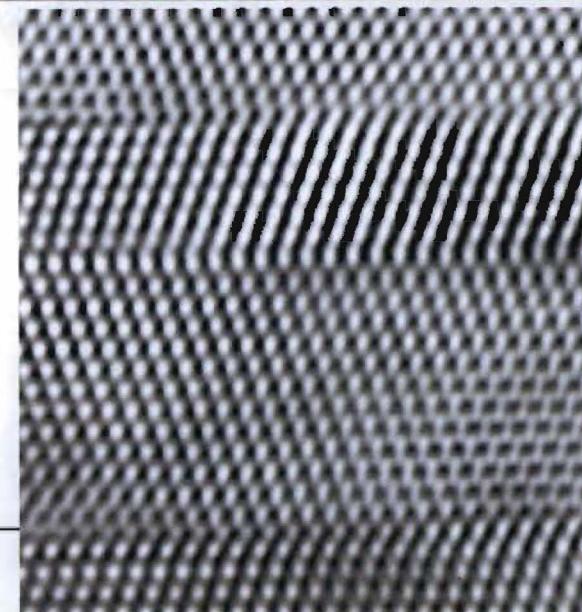
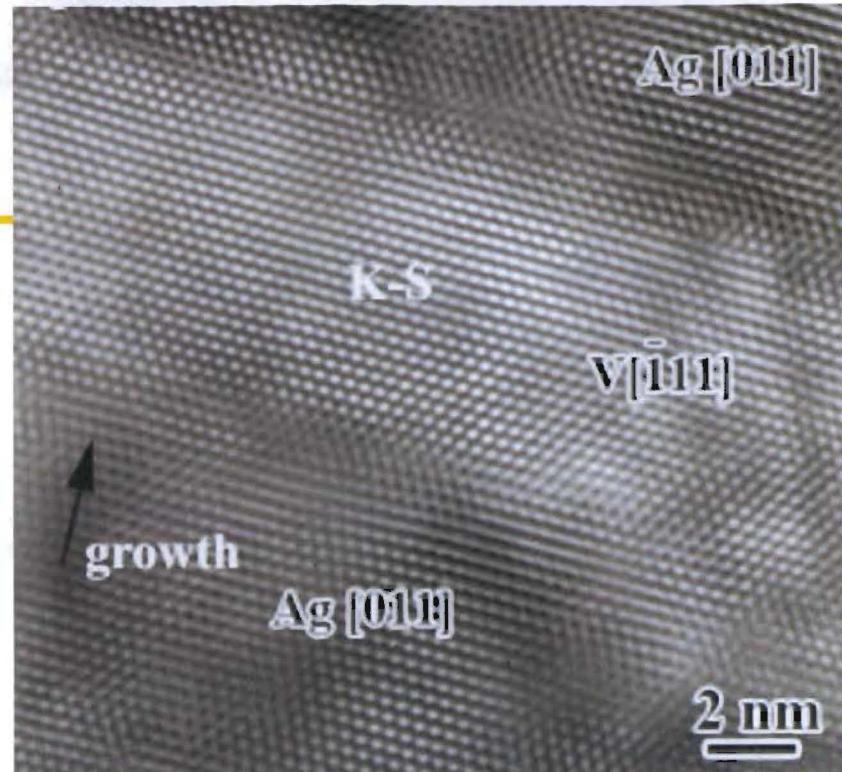
## Materials Investigated

- FCC-BCC multilayers:  
Kurdjumov-Sachs  
orientation relationship:  
 $\{111\}_{\text{fcc}} // \{110\}_{\text{bcc}} // \text{interface}$   
 $\langle 011 \rangle_{\text{fcc}} // \langle 111 \rangle_{\text{bcc}}$ .

V-Ag ( $\varepsilon = 9.7\%$ ), Cu-Nb ( $\varepsilon = 11\%$ ),  
Cu-Mo ( $\varepsilon = 6.2\%$ ), Cu-V ( $\varepsilon = 2.4\%$ ).

- $\Sigma 3 \{111\}$  coherent twin boundary in Cu

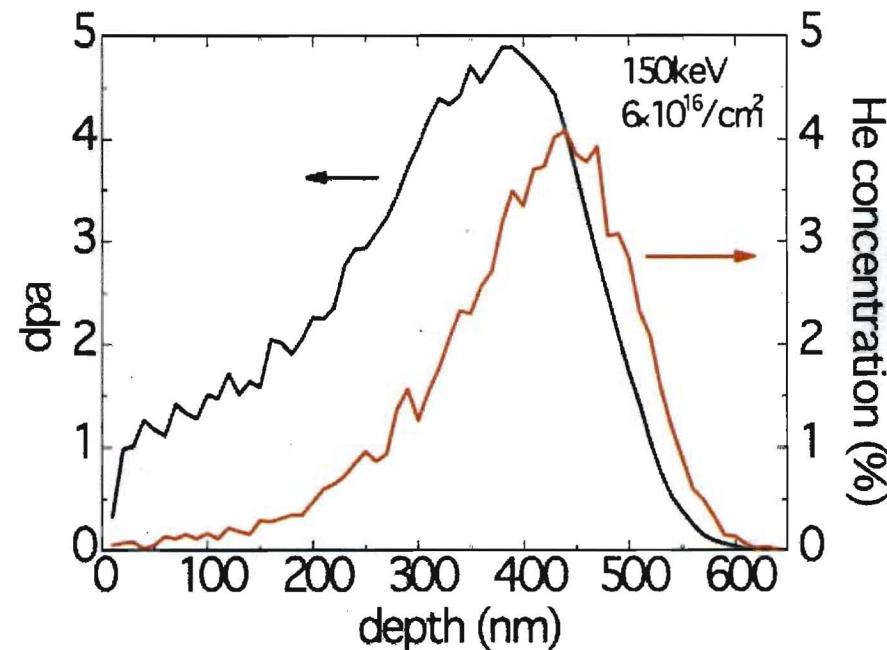
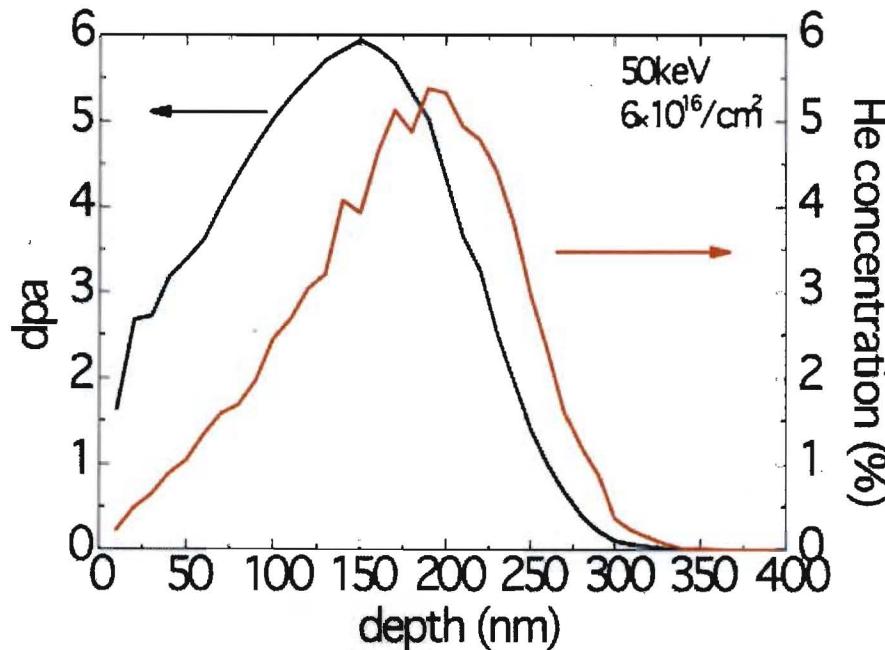
- Single layer metal metals (Cu, Nb,...)



# Helium Ion Implantation Experiments

(room temperature implants)

Calculations using software SRIM (Stopping and Range of Ions in Matter), James Ziegler



Profiles were measured experimentally by a variety of techniques:  
Elastic Recoil Detection (ERD)  
Nuclear Reaction Analysis (NRA): implants were  $\text{He}^{3+}$   
Secondary Ion Mass Spectroscopy (SIMS)

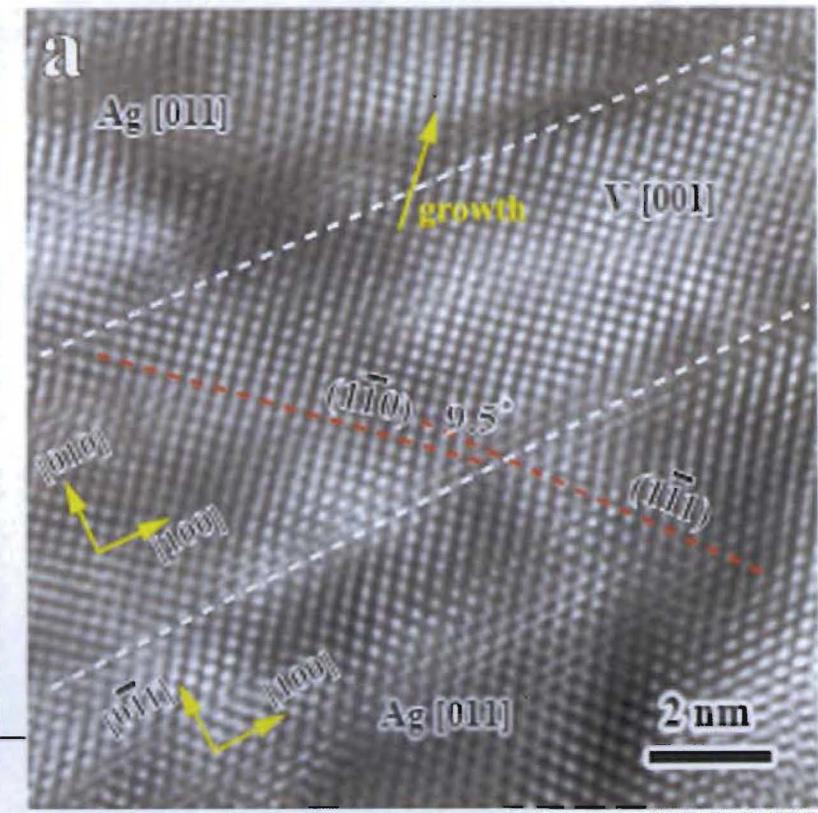
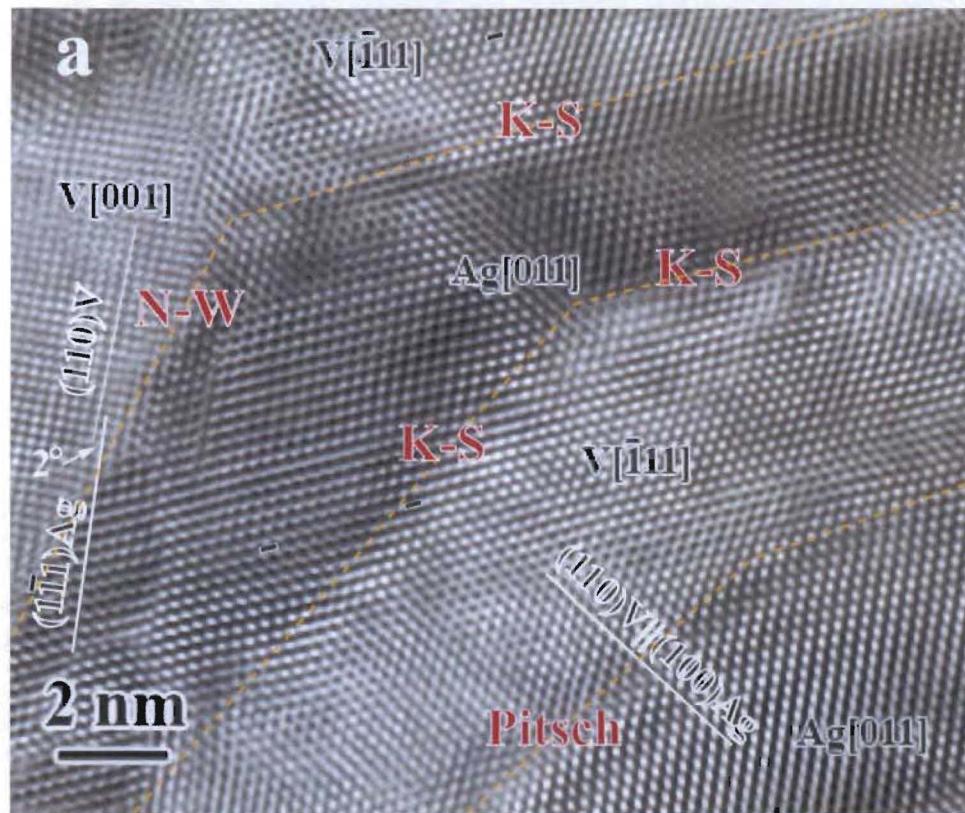
# Multiple orientation relationships observed in V-Ag

Kurdjumov-Sachs:  $\{111\}_{\text{fcc}} \parallel \{110\}_{\text{bcc}}$  &  $\langle 011 \rangle_{\text{fcc}} \parallel \langle 111 \rangle_{\text{bcc}}$

Nishiyama-Wasserman:  $\{111\}_{\text{fcc}} \parallel \{110\}_{\text{bcc}}$  &  $\langle 011 \rangle_{\text{fcc}} \parallel \langle 001 \rangle_{\text{bcc}}$

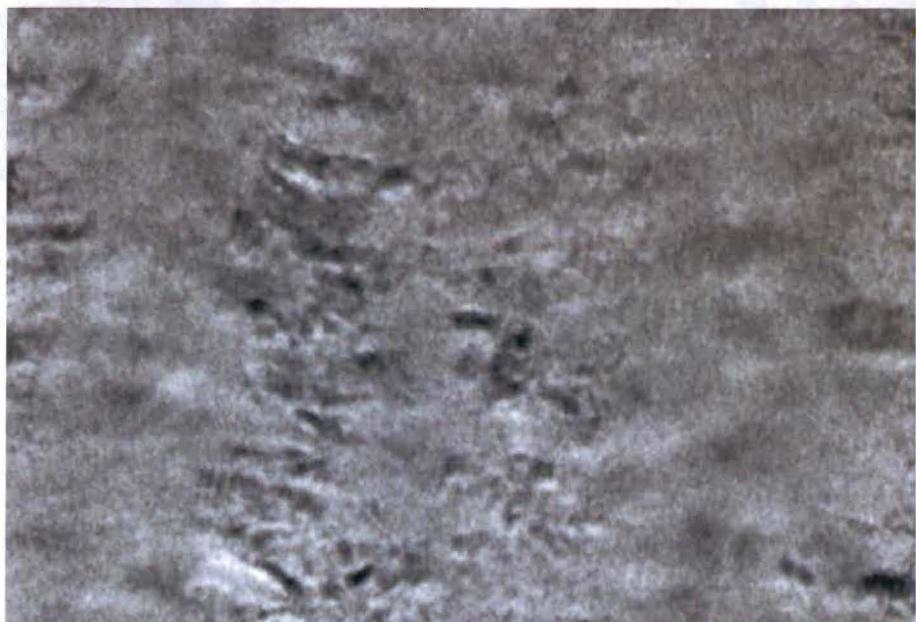
Bain Orientation:  $\{100\}_{\text{fcc}} \parallel \{100\}_{\text{bcc}}$  &  $\langle 011 \rangle_{\text{fcc}} \parallel \langle 001 \rangle_{\text{bcc}}$

Pitsch orientation:  $\{100\}_{\text{fcc}} \parallel \{110\}_{\text{bcc}}$  &  $\langle 110 \rangle_{\text{fcc}} \parallel \langle 111 \rangle_{\text{bcc}}$

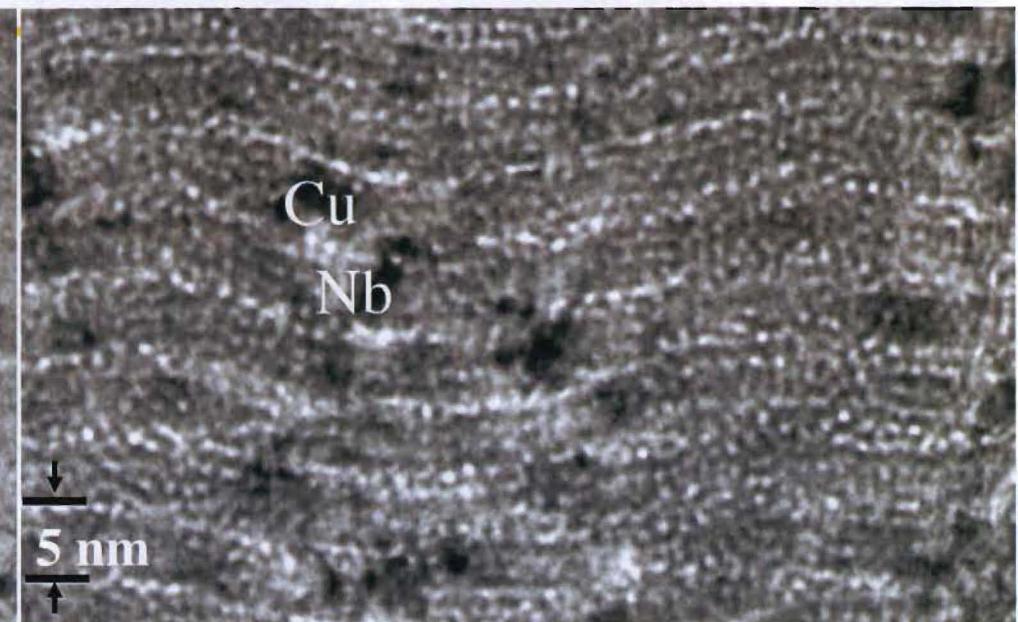


## Through-focus imaging in TEM is used to detect helium bubbles

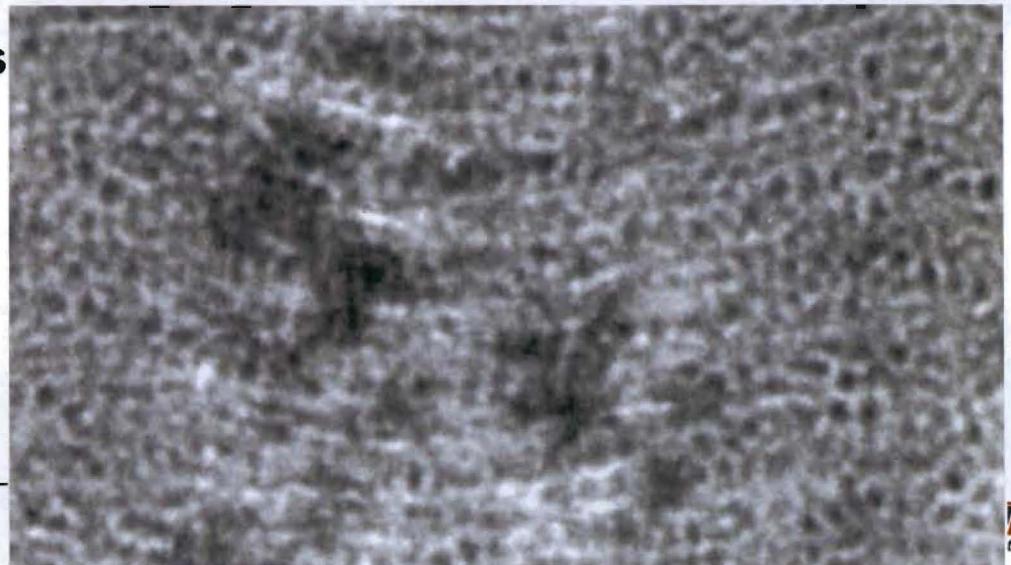
Near-focus



Under-focus



Over-focus



Room temperature He implantation,  
Energy: 35 keV, Dose:  $1 \times 10^{17} / \text{cm}^2$ ;

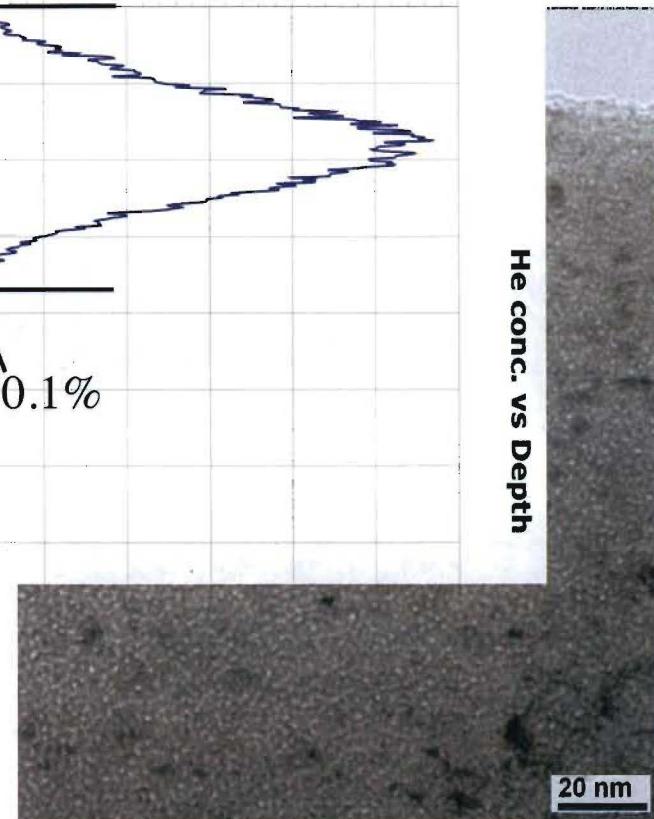
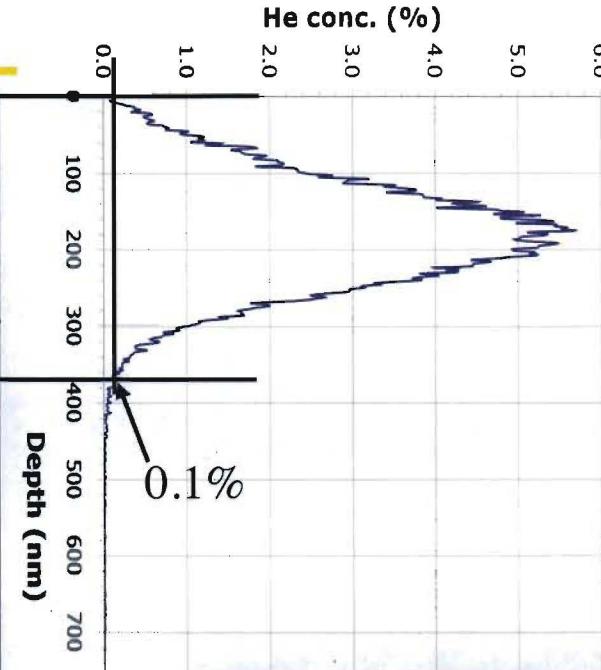
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# He Ion Implantation Damage in Pure Cu

He ions at 35 keV and  $1 \times 10^{17}/\text{cm}^2$



BF TEM image of the full thickness of a pure Cu film -

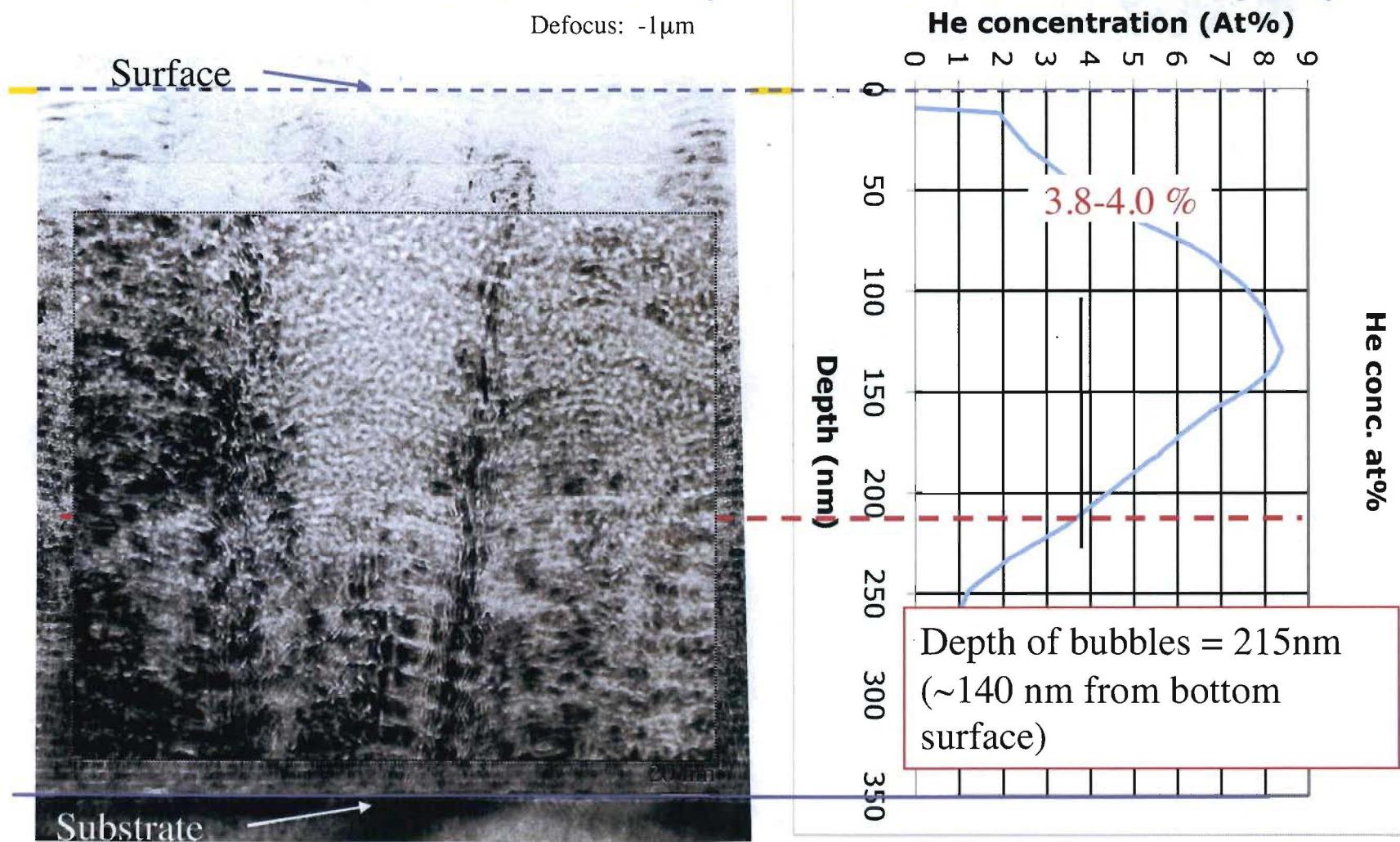


Upper region of the film - He bubbles start to form near the top surface

**Bubbles detected at helium concentrations  $\ll 0.1$  at.%**

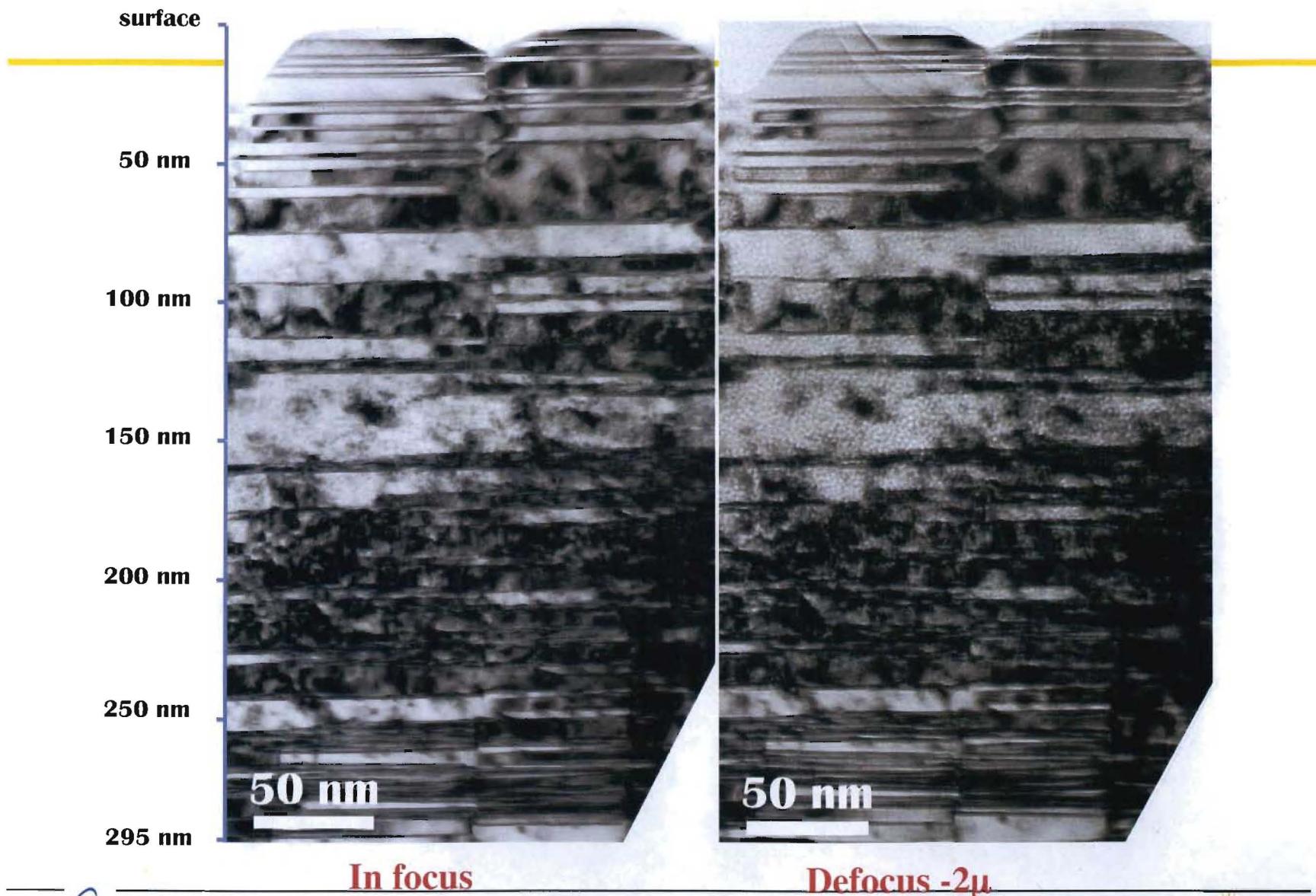
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In 2.5 nm Cu/Nb multilayers, bubbles are detected when Helium concentration exceeds  $\approx 4$  at.% (twice that of 5 nm multilayers)



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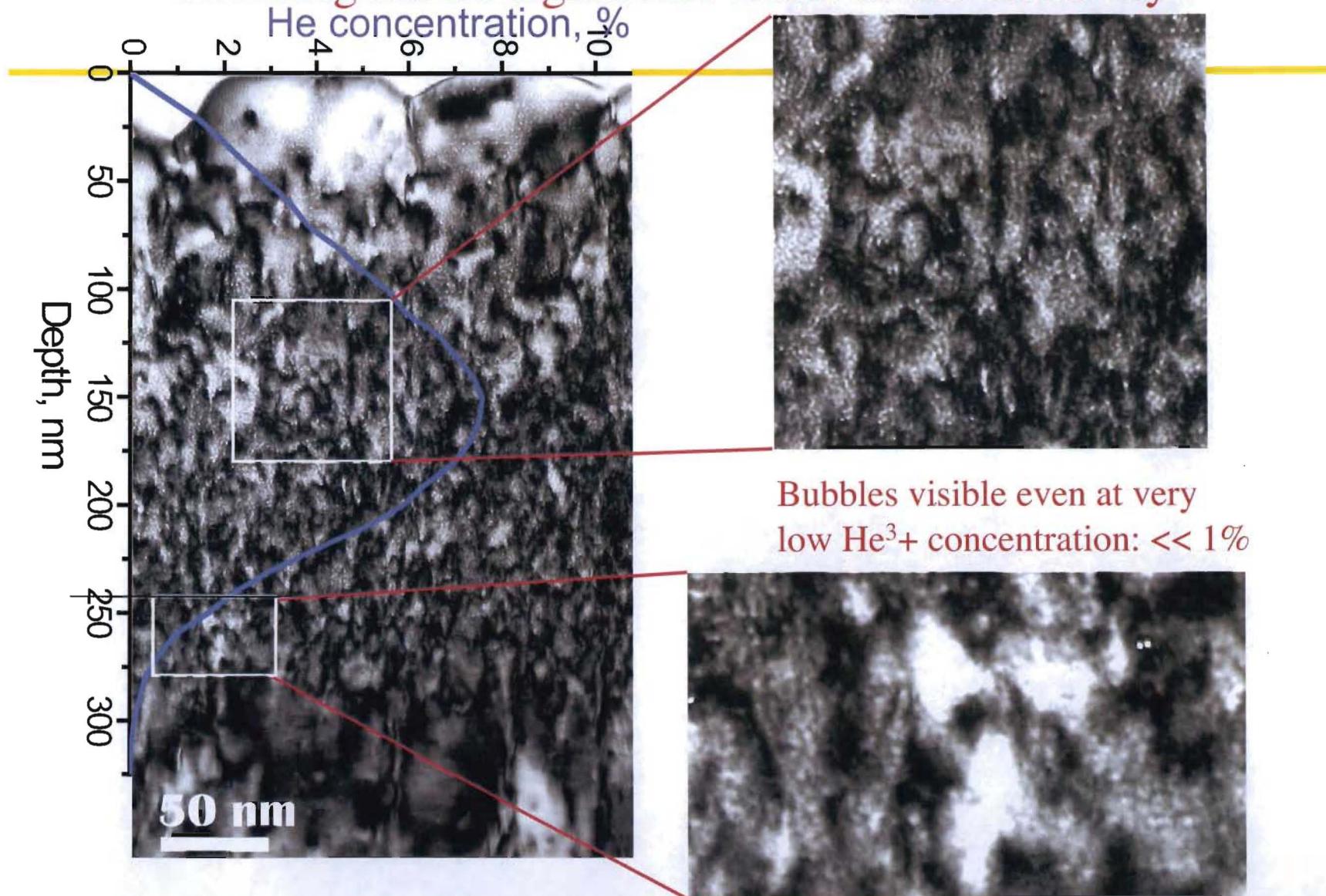
# Bubble formation in Nano-twinned Cu



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## Bubble distribution vs He concentration

Twinning has no significant effect on He solubility



## Critical Helium Concentration at which Bubbles are Resolved

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**Pure metals**  $\approx 100\text{-}1000$  appm

$\Sigma 3\{111\}$  coherent twin boundary <0.1 at.%

**Cu-V (2.5 nm)**  $\approx 1$  at.%

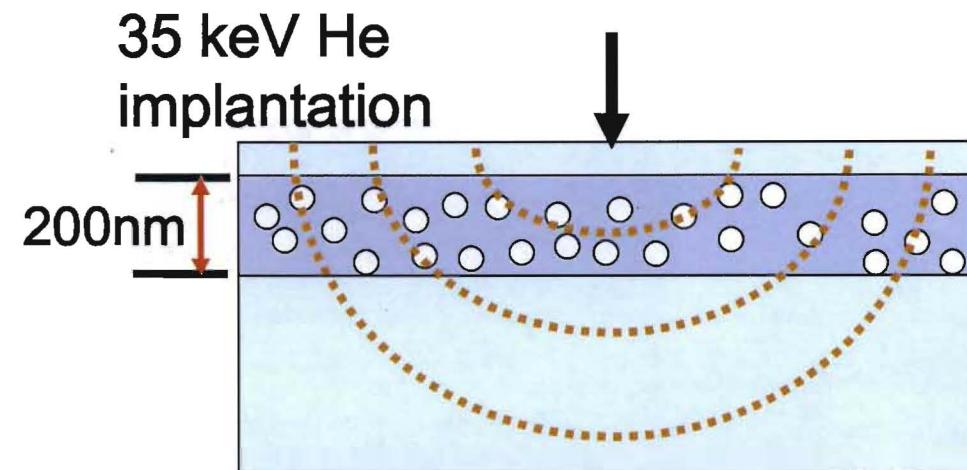
**Cu-Mo (5 nm)**  $\approx 0.7$  at.%; estimate  $\approx 1.4$  at.% for 2.5 nm layers

**Cu-Nb (2.5 nm)**  $\approx 4$  at.%

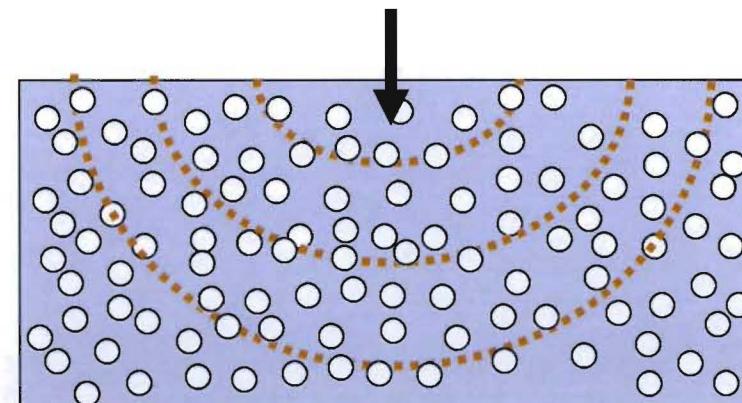
**V-Ag (2.5 nm)**  $\approx 4\text{-}5$  at.%

## Objective #2: Explore the effect of ion implantation induced defects (particularly He bubbles) on irradiation hardening

Implantation with a single ion energy produces a narrow zone containing He bubbles.



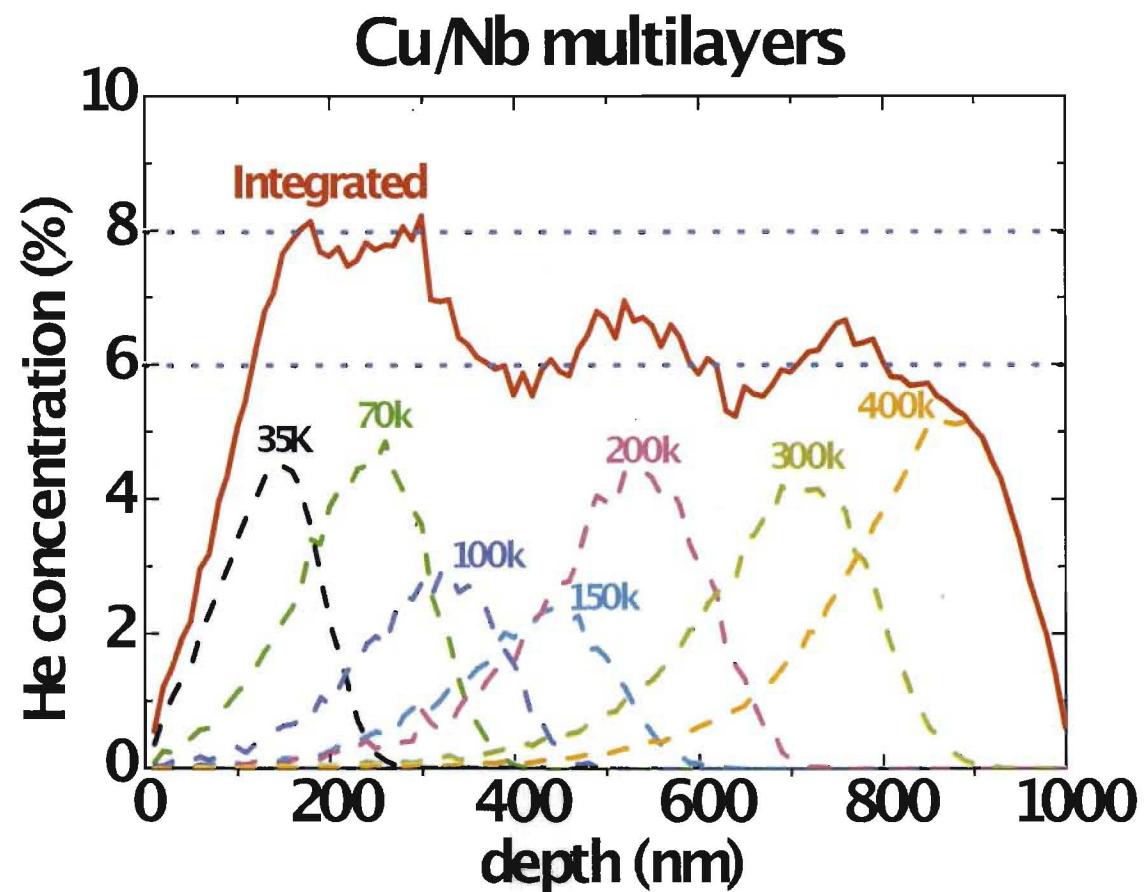
Desired bubble distribution for measuring mechanical response.



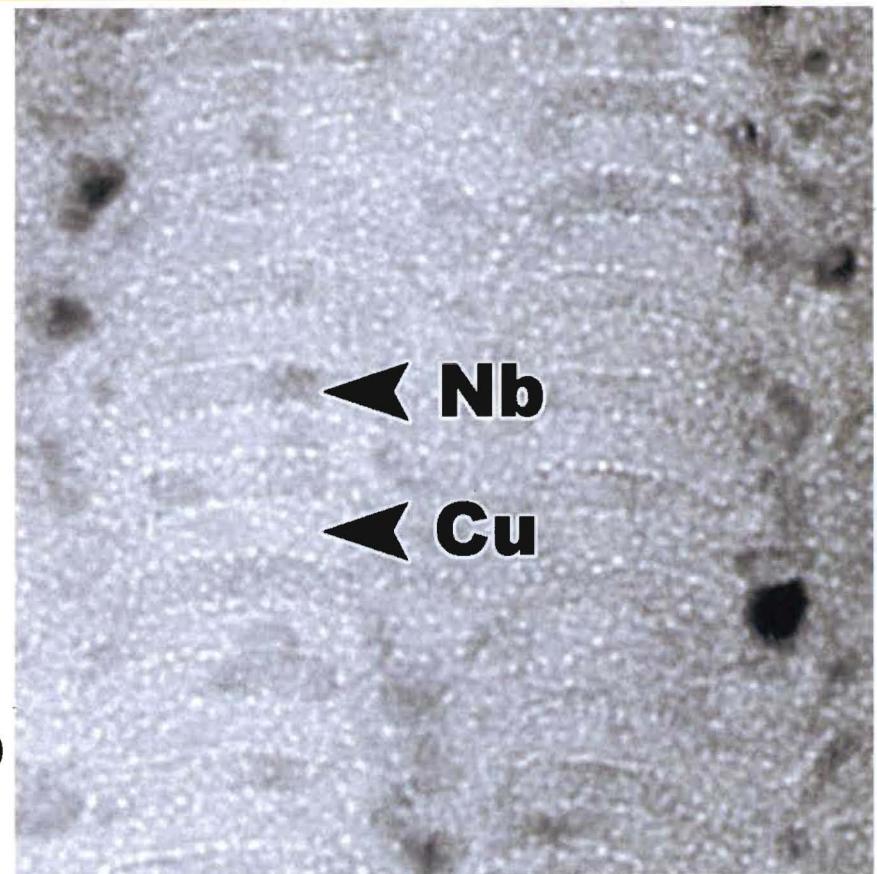
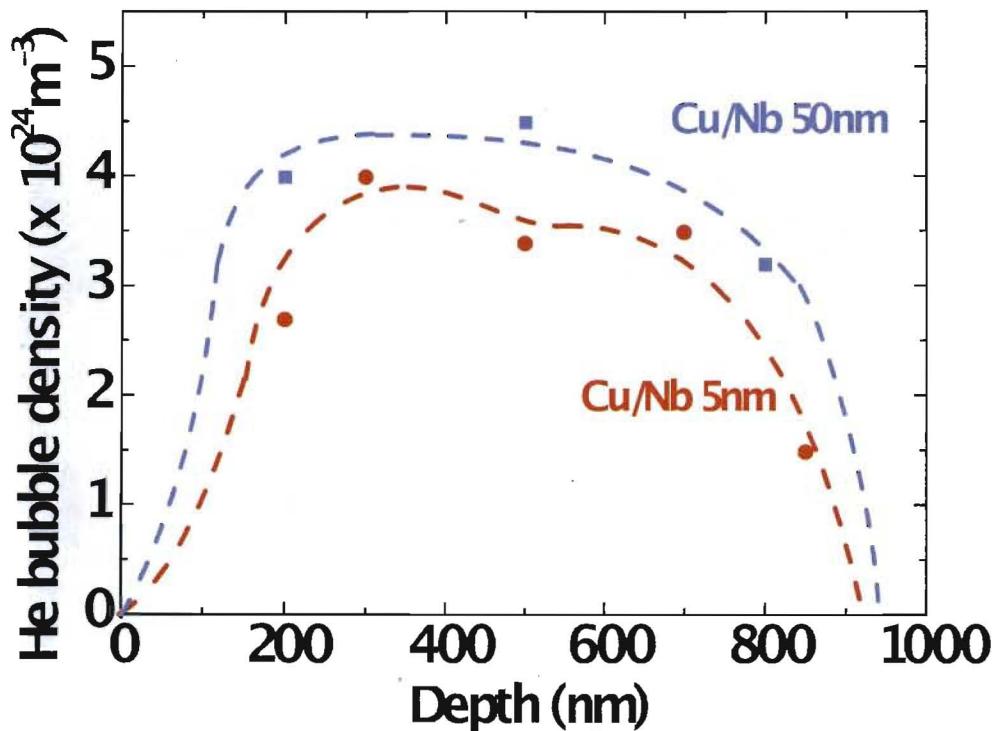
**Experiment design:** A series of implants of different energies were used to produce uniform helium bubble distribution over 1 um depth

Sample: Cu, Nb,  
Cu/Nb 50 nm, Cu/Nb 5 nm,  
Cu/Nb 2.5 nm.

- #1: 400 keV -  $9 \times 10^{16}$  ion·cm<sup>-2</sup>
- #2: 300 keV -  $7 \times 10^{16}$  ion·cm<sup>-2</sup>
- #3: 200 keV -  $7 \times 10^{16}$  ion·cm<sup>-2</sup>
- #4: 150 keV -  $3.5 \times 10^{16}$  ion·cm<sup>-2</sup>
- #5: 100 keV -  $4 \times 10^{16}$  ion·cm<sup>-2</sup>
- #6: 70 keV -  $6 \times 10^{16}$  ion·cm<sup>-2</sup>
- #7: 35 keV -  $4 \times 10^{16}$  ion·cm<sup>-2</sup>

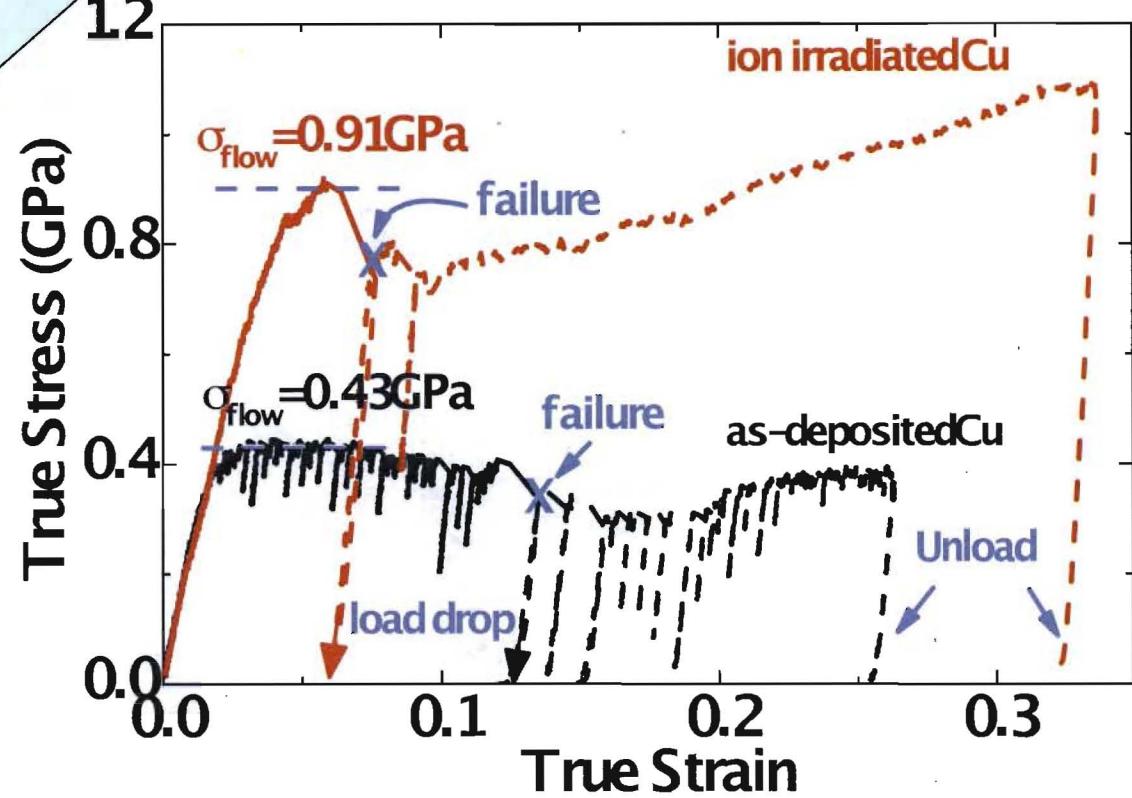
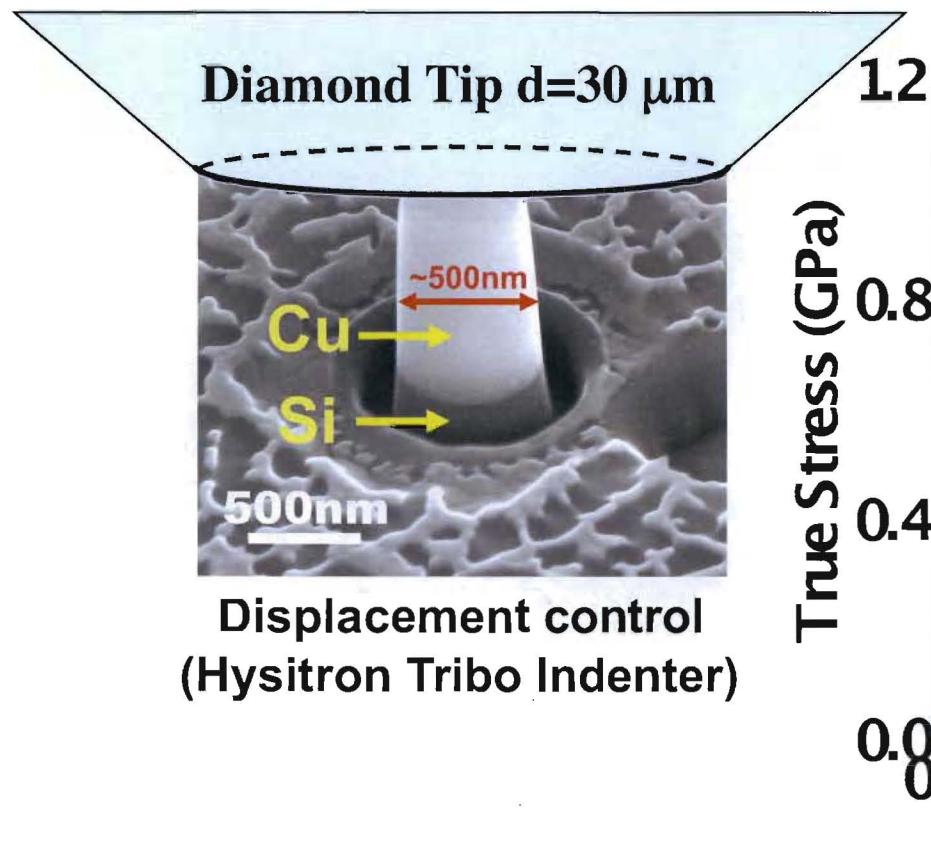


## He bubble density as measured from TEM images decreases with decreasing layer thickness

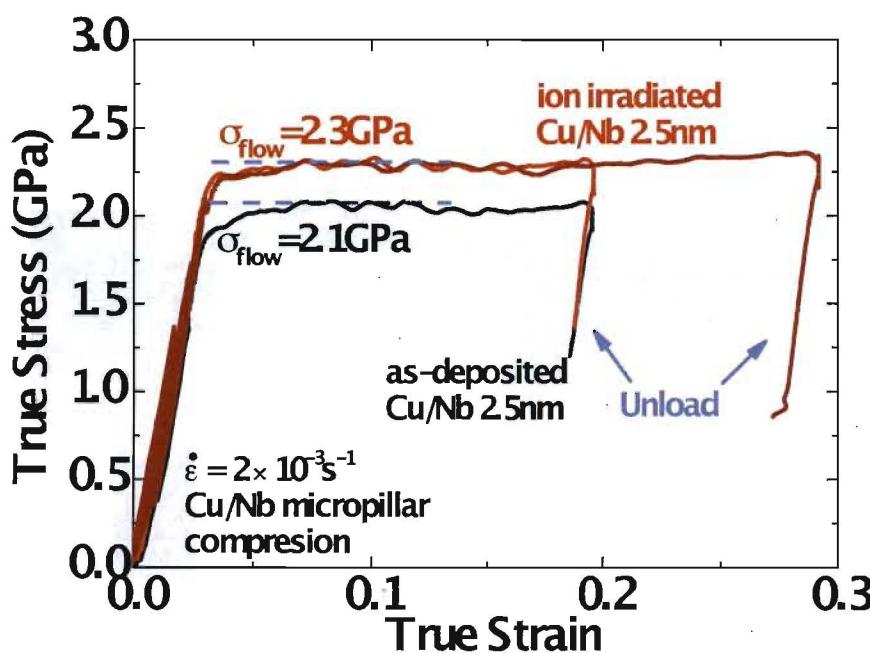


# Pillar compression test – sputtered Cu with He bubbles

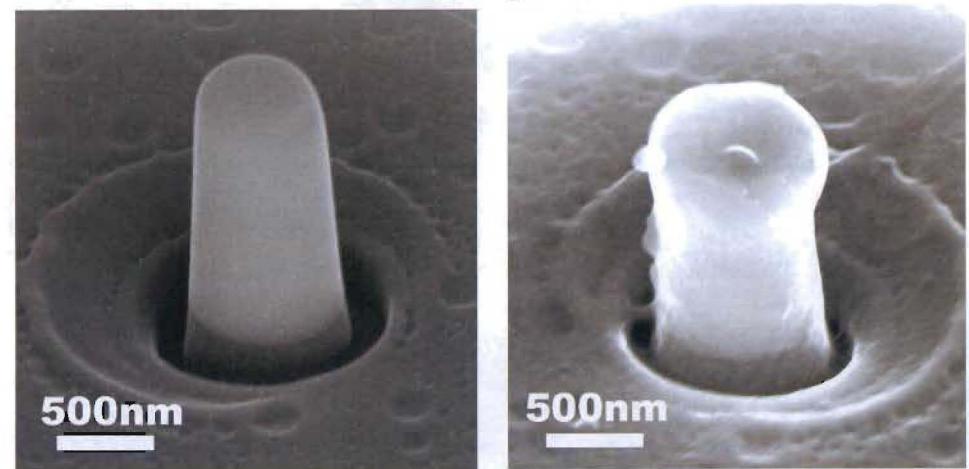
Significant hardening with reduced deformability



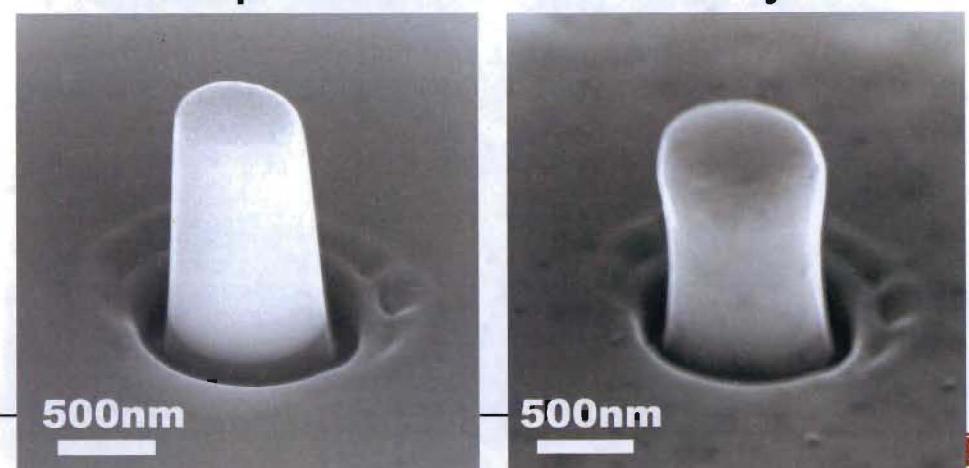
# In multilayers, irradiation hardening decreases with decreasing layer thickness



Ion irradiated Cu/Nb 2.5nm  
multilayers

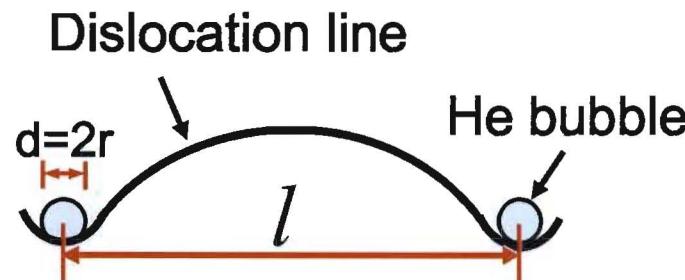


As-dep Cu/Nb 2.5nm multilayers



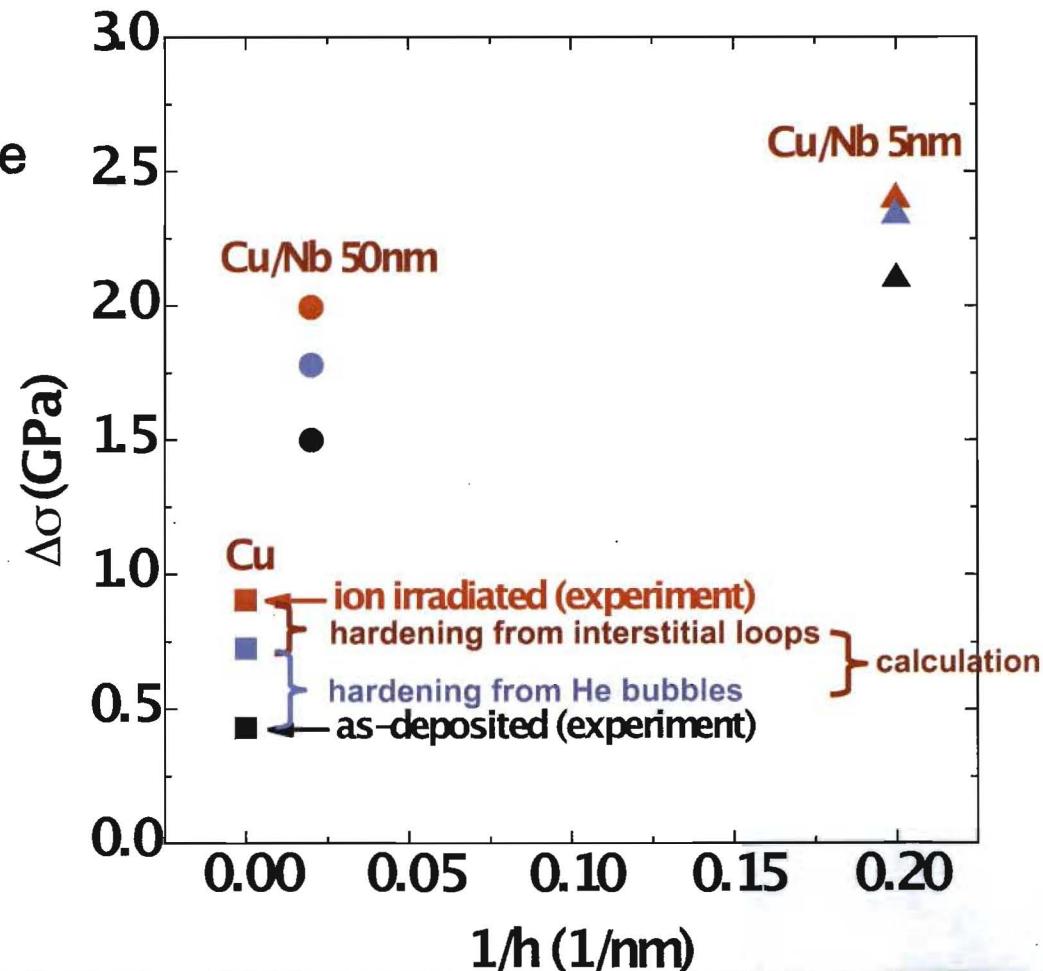
# Irradiation Hardening Mechanisms

- Pressurized He bubbles



$$\Delta\tau = \alpha \frac{2\xi}{b(l - 2r)}$$

$$= \alpha \frac{\mu b}{2\pi(l - 2r)} \ln\left(\frac{r}{b}\right)$$



## Summary

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- The critical He concentration at which bubbles are resolved in TEM is orders of magnitude higher in fcc-bcc nanolayered composites than in pure metals. This implies increased He solubility at fcc-bcc interfaces that may originate from the atomic structure of the interface. By comparison, coherent twin boundaries appear to have low solubility for helium.
- Density of radiation induced bubbles and interstitial loops, and barrier strength of bubbles decrease with reducing layer thickness. Consequently, the magnitude of hardening in helium ion implanted multilayers decreases significantly with decreasing layer thickness.